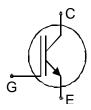


# IGBT Chip in NPT-technology

## FEATURES:

- 600V NPT technology
- 100µm chip
- positive temperature coefficient
- easy paralleling

- This chip is used for:
- IGBT Modules
- Applications:
- drives



Chip Type	V <sub>CE</sub>	I <sub>Cn</sub>	Die Size	Package	Ordering Code
SIGC11T60NC	600V	10A	3.25 x 3.25 mm <sup>2</sup>	sawn on foil	Q67050-A4158- A001

## MECHANICAL PARAMETER:

Raster size	3.25 x 3.25	mm <sup>2</sup>			
Area total / active	10.6 / 7.4				
Emitter pad size	2 x 1.6				
Gate pad size	1.08 x 0.68				
Thickness	100	μm			
Wafer size	150	mm			
Flat position	0	deg			
Max.possible chips per wafer	1414				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	Al, ≤500µm				
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



### MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V <sub>CE</sub>	600	V
DC collector current, limited by T <sub>jmax</sub>	I <sub>C</sub>	1)	А
Pulsed collector current, t <sub>p</sub> limited by T <sub>jmax</sub>	I <sub>cpuls</sub>	30	А
Gate-emitter voltage	V <sub>GE</sub>	±20	V
Operating junction and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55 +150	°C

<sup>1)</sup> depending on thermal properties of assembly

**STATIC CHARACTERISTICS** (tested on chip),  $T_j$ =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	V <sub>(BR)CES</sub>	V <sub>GE</sub> =0V, I <sub>C</sub> =500µA	600			
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	V <sub>GE</sub> =15V, I <sub>C</sub> =10A	1.7	2.0	2.5	V
Gate-emitter threshold voltage	V <sub>GE(th)</sub>	$I_C$ =350µA, $V_{GE}$ = $V_{CE}$	4.5	5.5	6.5	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =600V, V <sub>GE</sub> =0V			0.8	μA
Gate-emitter leakage current	I <sub>GES</sub>	$V_{CE}=0V, V_{GE}=20V$			120	nA

## DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Falameter			min.	typ.	max.	
Input capacitance	Ciss	$V_{CE}=25V$	-	550	-	pF
Output capacitance	Coss	$V_{GE}=0V$	-	62	-	
Reverse transfer capacitance	Crss	<i>f</i> =1MHz	-	42	-	

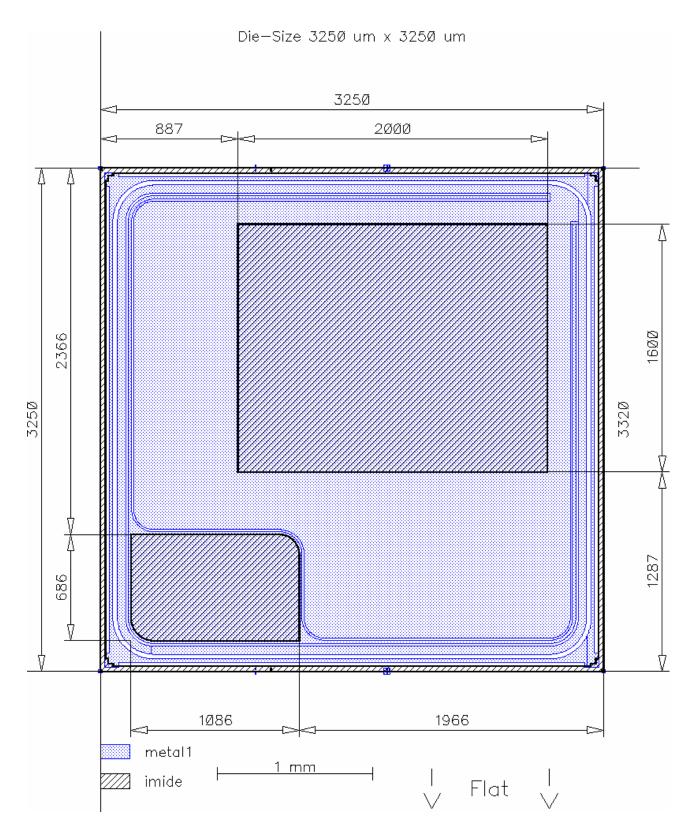
## **SWITCHING CHARACTERISTICS** (tested at component), Inductive Load:

Parameter	Symbol	Conditions <sup>1)</sup>	Value			Unit
			min.	typ.	max.	onne
Turn-on delay time	t <sub>d(on)</sub>	<i>T</i> <sub>j</sub> =125°C V <sub>CC</sub> =300V	-	20	-	ns
Rise time	<i>t</i> r	/ <sub>C</sub> =10A	-	8	-	
Turn-off delay time	$t_{d(off)}$	$V_{GE}=\pm 15/V$ $R_{G}=27\Omega$	-	110	-	
Fall time	t <sub>f</sub>		-	20	-	

<sup>1)</sup> values also influenced by parasitic L- and C- in measurement and package.



## **CHIP DRAWING:**



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## FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

tbd

### Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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